

**Dual N-Channel Enhancement Mode MOSFET**
**◆ DESCRIPTION**

The MT9926 uses advanced technology to provide excellent  $R_{DS(ON)}$ , low switching loss and reasonable price.

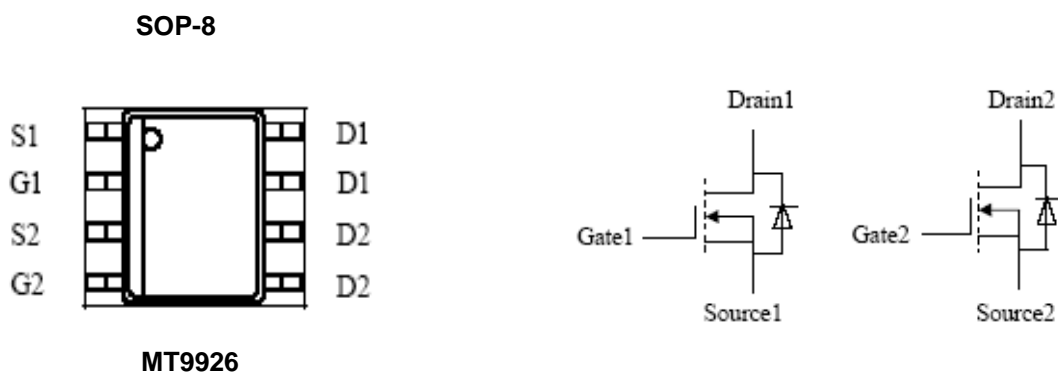
This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits, and low in-line power loss are needed in a very small outline surface mount package.

**◆ FEATURES**

- $V_{DS} = 20V$
- $R_{DS(ON)}, V_{GS} @ 2.5V, I_{DS} @ 5.2A = 40m\Omega$
- $R_{DS(ON)}, V_{GS} @ 4.5V, I_{DS} @ 6A = 28m\Omega$
- Advanced trench process technology
- High Density Cell Design For Ultra Low On-Resistance
- High power and Current handing capacity.
- Fully Characterized Avalanche Voltage and Current

**◆ APPLICATIONS**

- POWER Management in Notebook
- Portable Equipment
- Battery Powered System

**◆ PIN CONFIGURATION**


**Dual N-Channel Enhancement Mode MOSFET**
**◆ ABSOLUTE MAXIMUM RATINGS**

 (T<sub>A</sub>=25°C Unless Otherwise Noted)

Parameter	Symbol	Maximum	Unit
Drain-Source Voltage	V <sub>DS</sub>	20	V
Gate-Source Voltage	V <sub>GS</sub>	± 12	V
Continuous Drain Current	I <sub>D</sub>	6	A
Pulsed Drain Current	I <sub>DM</sub>	20	A
Maximum Power Dissipation	P <sub>D</sub>	T <sub>A</sub> = 25 °C	2.0
		T <sub>A</sub> = 75 °C	1.3
Operating junction temperature range	T <sub>J</sub>	150	°C
Storage temperature range	T <sub>STG</sub>	- 55 to 150	°C

**◆ THERMAL RESISTANCE RATINGS**

Thermal Resistance	Symbol	Maximum	Unit
Junction-to-Ambient	R <sub>θJA</sub>	62.5	°C/W

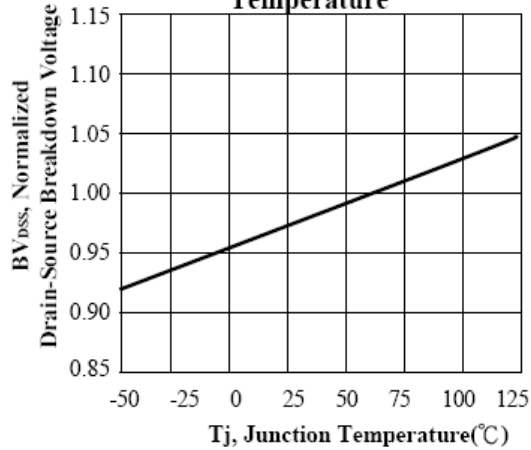
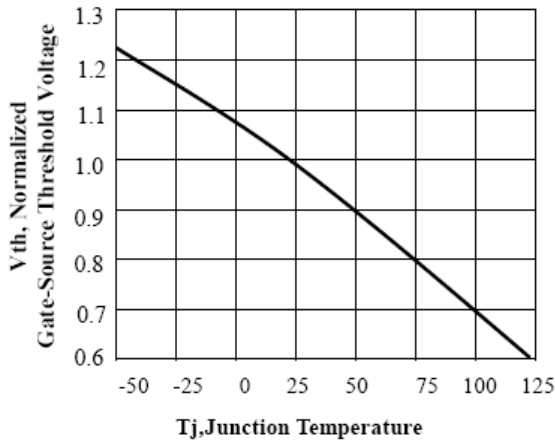
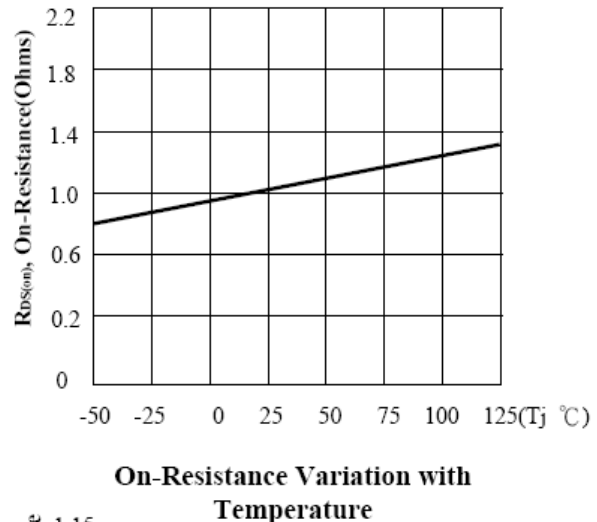
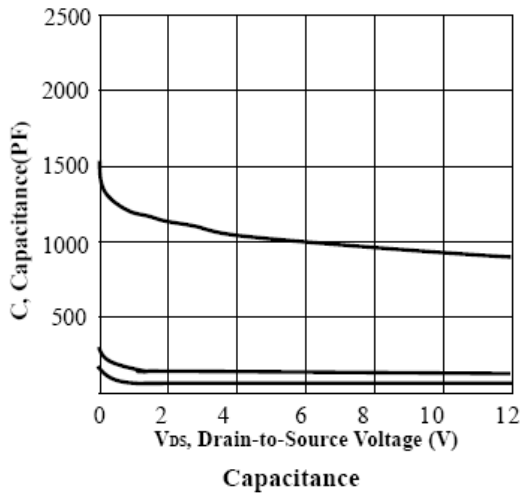
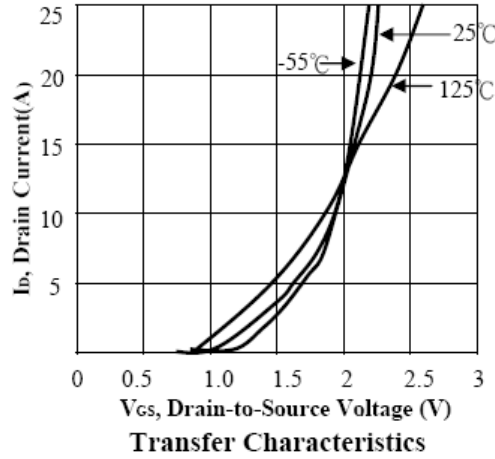
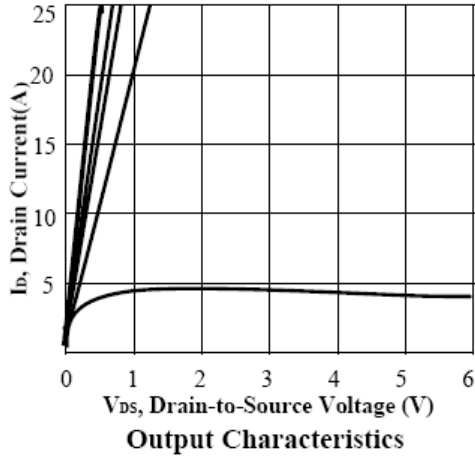
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**◆ ELECTRICAL CHARACTERISTICS**

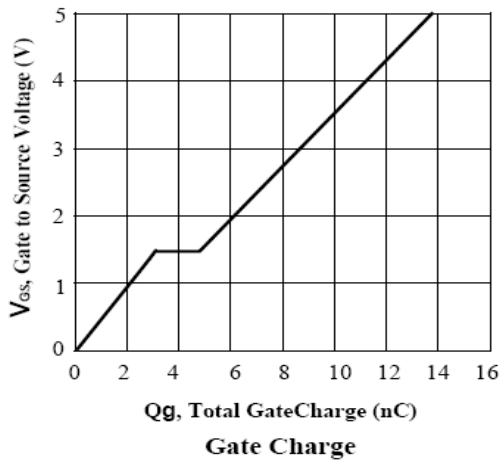
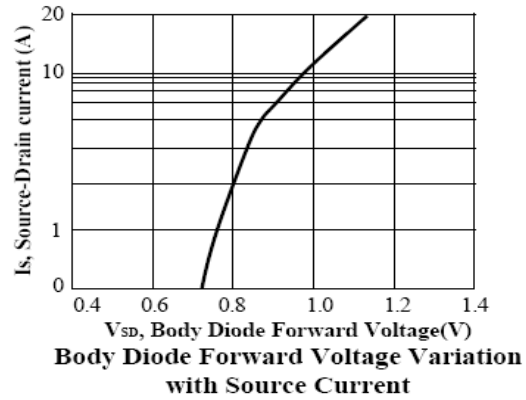
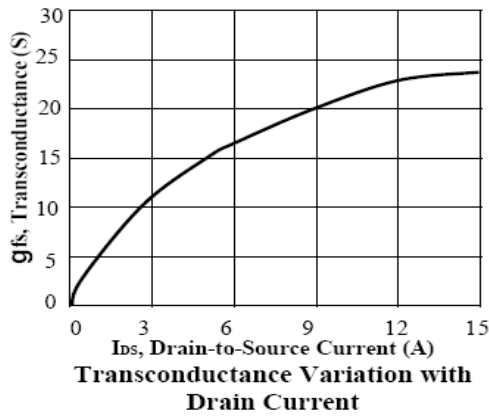
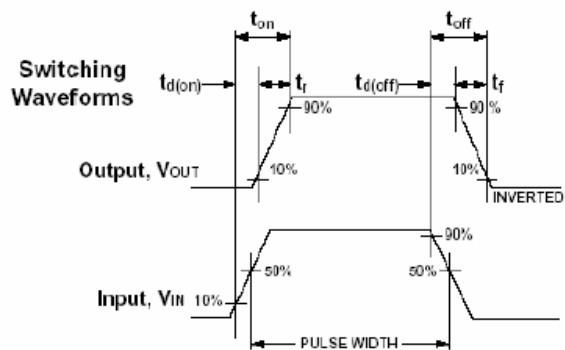
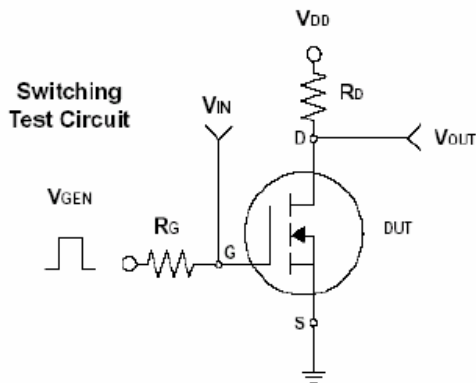
 (T<sub>A</sub>=25°C Unless Otherwise Noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250 μA	20	-	-	V
Drain-Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 6 A	-	22	28	mΩ
		V <sub>GS</sub> = 2.5V, I <sub>D</sub> = 5.2 A	-	30	40	
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA	0.6	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0 V	-	-	1	μA
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ± 12 V,	-	-	±100	nA
Diode Forward Voltage	g <sub>fs</sub>	I <sub>D</sub> = 6 A, V <sub>DS</sub> = 10V	7	13	-	S
<b>Dynamic Characteristics <sup>(2)</sup></b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 6A	-	4.86	-	nC
Gate Source Charge	Q <sub>gs</sub>		-	0.92	-	
Gate Drain Charge	Q <sub>gd</sub>		-	1.4	-	
Input Cap.	C <sub>iss</sub>	V <sub>DS</sub> = 8V, V <sub>GS</sub> = 0V f = 1MHz	-	562	-	pF
Output Cap.	C <sub>oss</sub>		-	106	-	
Reverse Transfer Cap.	C <sub>rss</sub>		-	75	-	
Turn-On Delay Time	T <sub>D(on)</sub>	V <sub>DD</sub> = 10V, V <sub>GEN</sub> = 4.5V, R <sub>G</sub> = 6Ω, I <sub>D</sub> = 1A,	-	8.1	-	nS
Turn-On Rise Time	T <sub>r</sub>		-	9.95	-	
Turn-Off Delay Time	T <sub>D(off)</sub>		-	21.85	-	
Turn-Off Fall Time	T <sub>f</sub>		-	5.35	-	
<b>Source-Drain Diode</b>						
Max. Diode Forward Current	I <sub>S</sub>		-	-	1.7	A
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1.7A	-	-	1.2	V

Note :

1. Pulse Test : Pulse width ≤ 300us , Duty Cycle ≤ 2%

**◆ TYPICAL CHARACTERISTICS**


**Dual N-Channel Enhancement Mode MOSFET**
**◆ TYPICAL CHARACTERISTICS**

**◆ TYPICAL APPLICATIONS**


**◆ PHYSICAL DIMENSIONS**
**8-Pin Plastic S.O.I.C.**
